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Expression of concern: Structural, morphological, electrical, and dielectric properties of $\text{Na}_2\text{Cu}_5(\text{Si}_2\text{O}_7)_2$ for ASSIBs

Mohamed Ben Bechir^{*a} and Mehdi Akermi^{bc}

Expression of concern for 'Structural, morphological, electrical, and dielectric properties of $\text{Na}_2\text{Cu}_5(\text{Si}_2\text{O}_7)_2$ for ASSIBs' by Mohamed Ben Bechir *et al.*, *RSC Adv.*, 2024, 14, 9228–9242, <https://doi.org/10.1039/D4RA01454E>.

RSC Advances is publishing this expression of concern in order to alert readers about concerns that have been raised regarding the BVS analysis and the NPD measurement. An expression of concern will continue to be associated with the article until a conclusive outcome is reached.

Laura Fisher
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Executive Editor, *RSC Advances*

^aLaboratory of Spectroscopic and Optical Characterization of Materials (LaSCOM), Faculty of Sciences, University of Sfax, 3000 Sfax, Tunisia. E-mail: mohamedbenbechir@hotmail.com

^bDepartment Physics, College of Sciences, Jazan University, P. O. Box 114, Jazan, Kingdom of Saudi Arabia. E-mail: makermi@jazanu.edu.sa

^cLaboratory of Interfaces and Advanced Materials, Faculty of Science, Boulevard of the Environment, University of Monastir, Monastir, Tunisia

